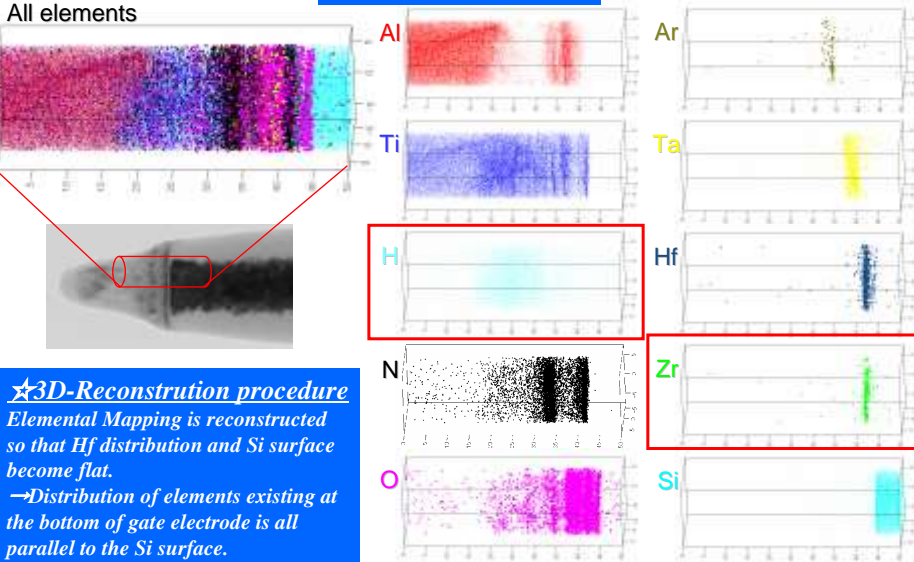


3-dimensional element mapping by 3DAP

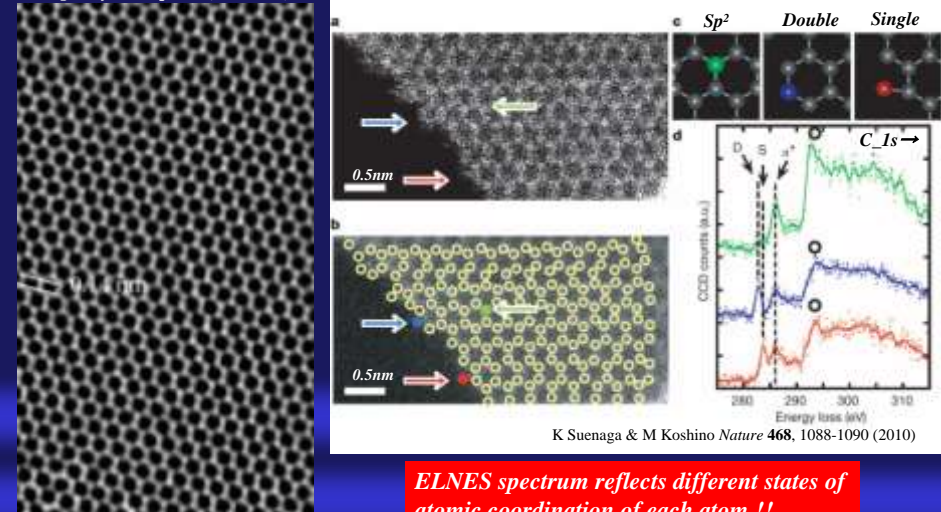
H and Zr are detected!!



Low KeV Cs-STEM analysis for nano-Carbon

HR-HAADF Image of Single layer Graphene(at 60KeV)

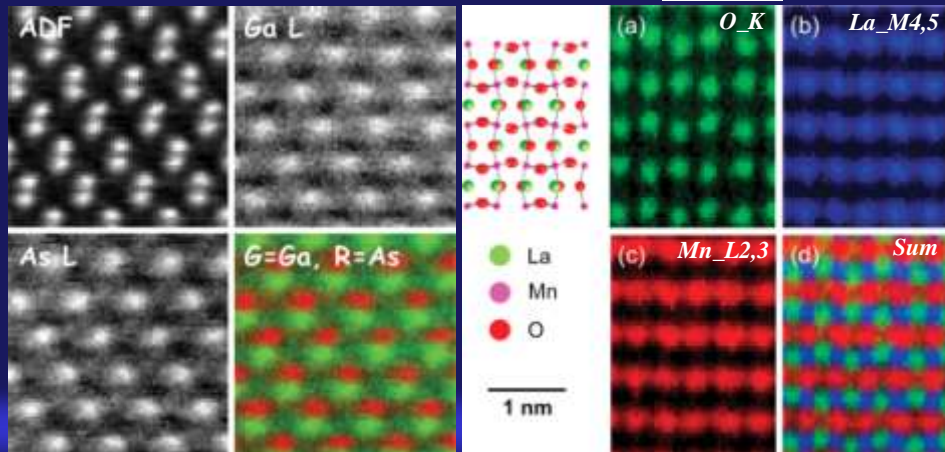
Single layer Graphene edge Spectroscopy(ELNES) at 60keV



Column by Column Spectroscopic Imaging by EELS

GaAs

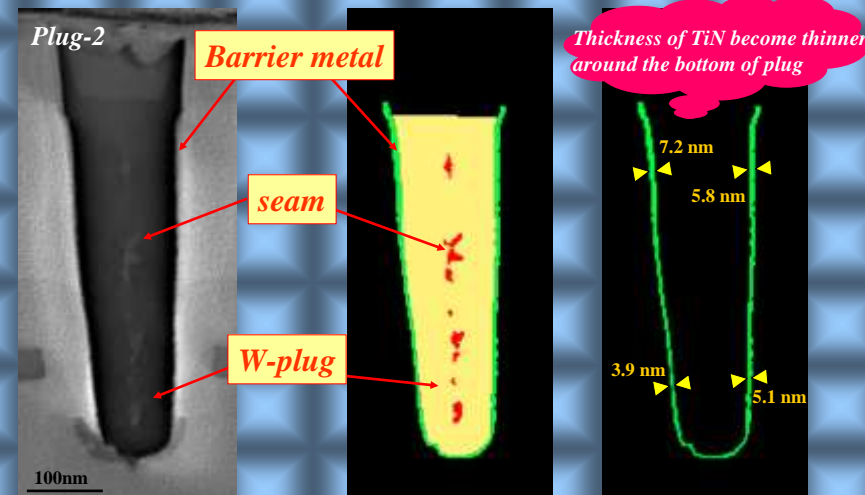
LaMnO3



Pennycook S J, Varela M J *Electron Microsc* **60**(2011) S213-S223

Identifies each constituent element in the crystal, has also captured a small displacement of them further.

Quantitative analysis of coverage of by 3-D TEM



Digital slice image

Extraction of TiN barrier metal

Coverage of TiN barrier metal and thickness at the each point can be obtained quantitative value by analysis of digital sliced images